

RF EXPOSURE REPORT

Applicant	Bellabeat.inc			
Address	2 Mint Plaza, San Francisco, CA 94103			
Manufacturer or Supplier	Bellabeat.inc			
Address	2 Mint Plaza, San Francisco, CA	94103		
Product	Spring			
Brand Name	N/A			
Model	Spring			
Additional Model & Model Difference	N/A			
Date of tests	Aug. 16, 2017 ~ Sep. 06, 2017			
FCC Part 2 (Sect	ion 2.1091)			
🔀 KDB 447498 D01				
⊠ IEEE C95.1				
CONCLUSION: The	submitted sample was found to g	COMPLY with the test requirement		
	Tested by Breeze JiangApproved by Glyn HeProject Engineer / EMC DepartmentSupervisor / EMC Department			
Breece		Date: Sep. 12, 2017		
This report is for your exclusive use. Any copying or replication of this report to or for any other person or entity, or use of our name or trademark, is permitted only with our prior written permission. This report sets forth our findings solely with respect to the test samples identified herein. The results set forth in this report are not indicative or representative of the quality or characteristics of the lot from which a test sample was taken or any similar or identical product unless specifically and expressly noted. Our report includes all of the tests requested by you and the results thereof based upon the information that you provided to us. You have 60 days from date of issuance of this report to notify us of any material error or omission caused by our negligence, provided, however, that such notice shall be in writing and shall specifically address the issue you wish to raise. A failure to raise such issue within the prescribed time shall constitute your unqualified acceptance of the completeness of this report, the tests conducted and the correctness of the report contents. Unless specification				

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RELEASE CONTROL RECORD

ISSUE NO.	REASON FOR CHANGE	DATE ISSUED	
FS170816N062	Original release	Sep. 12, 2017	



1. CERTIFICATION

FCC ID:	2AELF-SP01		
PRODUCT:	Spring		
BRAND NAME:	N/A		
MODEL NO.:	Spring		
ADDITIONAL NO.:	N/A		
TEST SAMPLE:	: Engineering Sample		
APPLICANT:	Bellabeat.inc		
STANDARDS:	FCC Part 2 (Section 2.1091)		
	KDB 447498 D01		
	IEEE C95.1		

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2. RF EXPOSURE DEFINE

The corresponding SAR Exclusion Threshold condition, listed below:

1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance,

mm)] $\cdot [\sqrt{f(GHz)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR,16 where

- > f(GHz) is the RF channel transmit frequency in GHz
- > Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

- 2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:
- a) [Threshold at 50 mm in step 1) + (test separation distance 50 mm) · (f(MHz)/150)] mW, at 100MHz to 1500 MHz
- b) [Threshold at 50 mm in step 1) + (test separation distance 50 mm) \cdot 10] mW at > 1500 MHz and \leq 6 GHz
- 3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.
 - a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by [1 + log(100/f(MHz))] for test separation distances > 50 mm and < 200 mm.
 - b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by ½ for test separation distances ≤ 50 mm.
 - c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.

3. CLASSIFICATION

The antenna of this product, under normal use condition, is at less than 20cm away from the body of the user. So, this device is classified as **Portable Device**.



4. SAR TEST EXCLUSION THRESHOLDS

The tuned conducted Average Power (declared by client)

Mode	Frequency (MHz)	Target Power (dBm)	Tolerance (dBm)	Lower Tolerance (dBm)	Upper Tolerance (dBm)	
BT-LE	2402-2480	-16	+-2	-18	-14	

The measured conducted Average Power

Mode	Frequency (MHz)	Averaged Power (dBm)		
BT-LE	2480	-15.28		

SAR Test Exclusion Thresholds

Mode	Frequency (MHz)	Maximum source-based time averaged conducted output power (dBm)	Minimum separation distance (mm)	Result of Eq. 1	Limit for 1-g SAR	Limit for 10-g extremit y SAR	Verdict
BT-LE	2402-2480	-14	5	0.0125	3.0	7.5	Exempt from SAR

Conclusion

Therefore this device complies with FCC's RF radiation exposure limits for general population without SAR evaluation.